

Wear-out failure analysis of an impedance-source PV microinverter based on system-level electrothermal modeling

Shen, Yanfeng; **Chub, Andrii**; Wang, Huai; **Vinnikov, Dmitri**; **Liivik, Elizaveta**; Blaabjerg, Frede IEEE transactions on industrial electronics 2019 / p. 3914-3927 <https://doi.org/10.1109/TIE.2018.2831643> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)